



JSM-7200F Schottky Field Emission Scanning Electron Microscope

Features

Specifications

Application

Related Products

Information

Specifications

	JSM-7200F	JSM-7200F with Low Vacuum mode (LV) * Option
Resolution (1 kV)	1.6 nm	
Resolution (20 kV)	1.0 nm	
Resolution (Analysis)	3.0 nm (15 kV, WD:10 mm, probe current:5 nA)	
Magnification	x10 to x1,000,000	
Accelerating voltage	0.01 to 30 kV	
Probe current	1 pA to 300 nA	
Detector (standard)	UED, LED	
Detector (optional)	USD, RBED	
Electron gun	In-lens Schottky field emission electron gun	
Aperture angle control lens	Built in	
Objective lens	Conical lens	

Specimen stage	Fully eucentric goniometer stage	
Stage movement	X: 70 mm, Y: 50 mm, Z: 2 to 41 mm, Tilt: -5 to 70°, Rotation: 360°	
Motor control	5 axes motor controlled	
Specimen exchange chamber	Maximum diameter : 100 mm Maximum height : 40 mm (vented with dry nitrogen)	
Large depth of focus (LDF)	Built in	
LV mode	-	Built in
LV detector	-	LV-BED, LV-SED (optional)
LV resolution	-	1.8 nm (30 kV)
Pressure in LV mode	-	10 Pa to 300 Pa
Orifice control	-	On the operation GUI
Introduced gas		Nitrogen
Evacuation system (SIP, TMP)	SIP x 2, TMP	
Evacuation system (RP)	RP x 1	RP x 2

Principal Options

Retractable Backscattered electron detector (RBED)

Upper secondary electron detector (USD)

Low vacuum secondary electron detector (LV-SED)

Energy dispersive X-ray spectrometry (EDS)
Electron backscatter diffraction (EBSD)
Wavelength dispersive X-ray spectrometry (WDS)
Large specimen stage (SS100S)
Specimen exchange chamber (Type1)
Stage navigation system (SNS)
Chamber camera
Operation table
SMile View
Soft X-ray Emission Spectrometer(SXES)

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